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Inventor Name Search Result

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Last Name = MATSUOKA

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Application#	Patent#	Status	Date Filed	Title	Inventor Name 10
<u>10823104</u>	Not Issued	020	04/13/2004	METHOD AND APPARATUS OF EVALUATING LAYER MATCHING DEVIATION BASED ON CAD INFORMATION	MATSUOKA, RYOICHI
<u>10607295</u>	Not Issued	020	06/26/2003	WAFERLESS METROLOGY RECIPE GENERATOR AND GENERATING METHOD	MATSUOKA, RYOICHI
<u>10147417</u>	<u>6757875</u>	150	05/16/2002	METHOD AND APPARATUS OF EVALUATING LAYER MATCHING DEVIATION BASED ON CAD INFORMATION	MATSUOKA, RYOICHI
<u>09934005</u>	Not Issued	161	08/20/2001	PATTERN DEFECT CHECKING METHOD AND DEVICE	MATSUOKA, RYOICHI
<u>09933785</u>	Not Issued	161	08/20/2001	MASK DEFECT CHECKING METHOD AND DEVICE FOR ELECTRON BEAM EXPOSURE	MATSUOKA, RYOICHI
<u>09903790</u>	Not Issued	030	07/12/2001	NAVIGATION METHOD AND DEVICE FOR PATTERN OBSERVATION OF SEMICONDUCTOR DEVICE	MATSUOKA, RYOICHI
<u>09903601</u>	Not Issued	030	07/12/2001	SEMICONDUCTOR WAFER PATTERN SHAPE EVALUATION METHOD AND DEVICE	MATSUOKA, RYOICHI
<u>09903600</u>	Not Issued	030	07/12/2001	WAFER PATTERN OBSERVATION METHOD AND DEVICE	MATSUOKA, RYOICHI
<u>09537945</u>	<u>6724929</u>	150	03/29/2000	WAFER INSPECTING APPARATUS	MATSUOKA, RYOICHI

<u>09537944</u>	Not Issued	161	03/29/2000	WAFER INSPECTING APPARATUS	MATSUOKA, RYOICHI
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